
**Polprevodniški elementi - Smernice za načrtovanje ocenjevanja zanesljivosti - 4.
del: Ocenjevanje zgodnjih odpovedi (IEC 63287-4:2026)**

Semiconductor devices - Guidelines for reliability qualification plans - Part 4: Early failure assessment (IEC 63287-4:2026)

Halbleiterbauelemente - Leitlinien für Zuverlässigkeitsqualifizierungspläne - Teil 4:
Frühzeitige Fehlerbewertung (IEC 63287-4:2026)

Dispositifs à semiconducteurs - Lignes directrices concernant les plans de qualification
de la fiabilité - Partie 4: évaluation des défaillances précoces (IEC 63287-4:2026)

Ta slovenski standard je istoveten z: EN IEC 63287-4:2026

ICS:

31.080.01	Polprevodniški elementi (naprave) na splošno	Semiconductor devices in general
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SIST EN IEC 63287-4:2026**en**

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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN IEC 63287-4

October 2026

ICS 31.080.01

English Version

**Semiconductor devices - Guidelines for reliability qualification
plans - Part 4: Early failure assessment
(IEC 63287-4:2026)**

Dispositifs à semiconducteurs - Lignes directrices
concernant les plans de qualification de la fiabilité - Partie 4:
Évaluation des défaillances précoces
(IEC 63287-4:2026)

Halbleiterbauelemente - Leitlinien für
Zuverlässigkeitsqualifizierungspläne - Teil 4: Frühzeitige
Fehlerbewertung
(IEC 63287-4:2026)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

EN IEC 63287-4:2026 (E)**European foreword**

The text of document 47/3025/FDIS, future edition 1 of IEC 63287-4, prepared by TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 63287-4:2026.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2027-10-31 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2029-10-31 document have to be withdrawn

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This document is read in conjunction with EN IEC 63287-1.

Any feedback and questions on this document should be directed to the users' national committee. A complete listing of these bodies can be found on the CENELEC website.

Endorsement notice

The text of the International Standard IEC 63287-4:2026 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standard indicated:

IEC 60068-2-1	NOTE	Approved as EN IEC 60068-2-1
IEC 60068-2-30	NOTE	Approved as EN IEC 60068-2-30
IEC 60749-11	NOTE	Approved as EN 60749-11

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 63287-1	-	Semiconductor devices - Generic semiconductor qualification guidelines - Part 1: Guidelines for IC reliability qualification	EN IEC 63287-1	-

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INTERNATIONAL STANDARD

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Part 4: Early failure assessment**

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